

EE241B : Advanced Digital Circuits

Lecture 21 – DVS II

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April 8, NY Times: Computers Already Learn From Us. But Can They Teach Themselves?



Scientists are exploring approaches that would help machines develop their own sort of common sense

Features Pieter Abbeel and Sergey Levine from UC Berkeley

Announcements

- Assignment 4 due next Friday.
- Reading
 - T. Burd, et al, JSSC, Nov 2000.

Outline

- Module 5
 - Dynamic voltage and frequency scaling

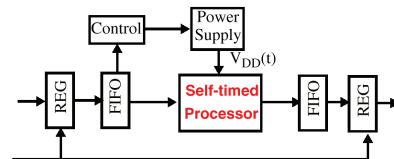


5.F Dynamic Voltage Scaling

Power /Energy Optimization Space

	Constant Throughput/Latency		Variable Throughput/Latency	
Energy	Design Time	Sleep Mode	Run Time	
Active	Logic design Scaled V_{DD} Trans. sizing Multi- V_{DD}	Clock gating	DFS, DVS	
Leakage	Stack effects Trans sizing Scaling V_{DD} + Multi- V_{Th}	Sleep T's Multi- V_{DD} Variable V_{Th} + Input control	DVS Variable V_{Th}	

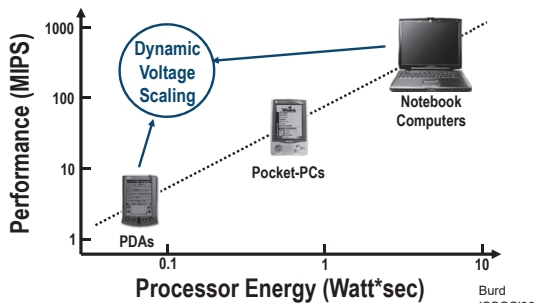
Adaptive Supply Voltages



Exploit Data Dependent Computation Times To Vary the Supply

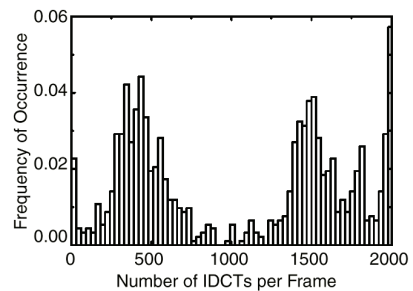
from [Nielsen94]
(IEEE Transactions on VLSI Systems)

Processors for Portable Devices

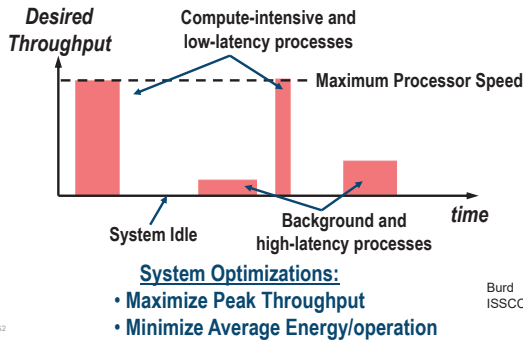


• Eliminate performance ↔ energy trade-off

Typical MPEG IDCT Histogram

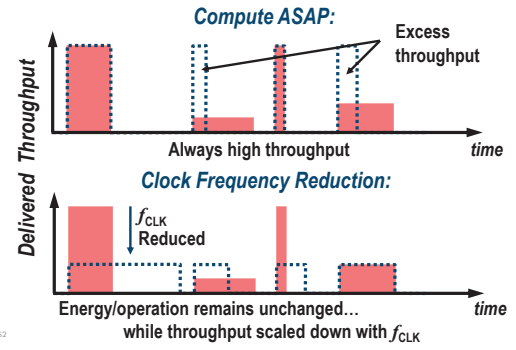


Processor Usage Model

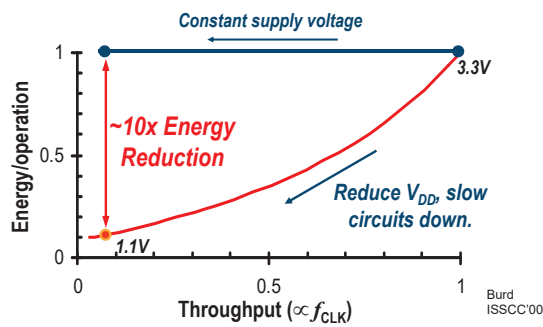


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Common Design Approaches (Fixed VDD)

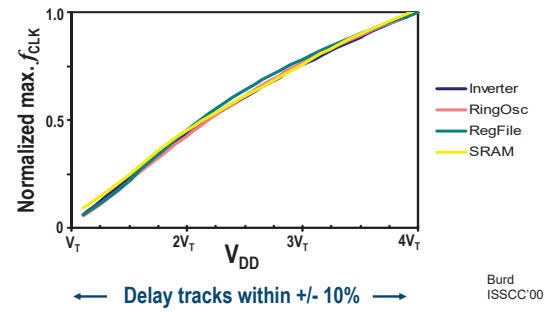


Scale V_{DD} with Clock Frequency



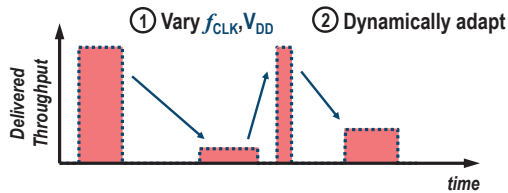
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CMOS Circuits Track Over V_{DD}



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Dynamic Voltage Scaling (DVS)

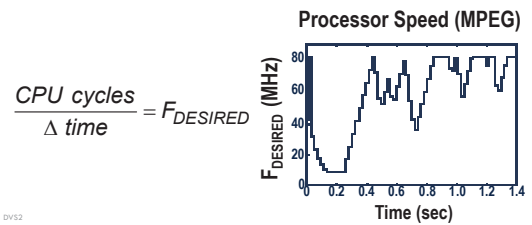


- Dynamically scale energy/operation with throughput.
- Always minimize speed → minimize average energy/operation.
- Extend battery life up to 10x with the exact same hardware!

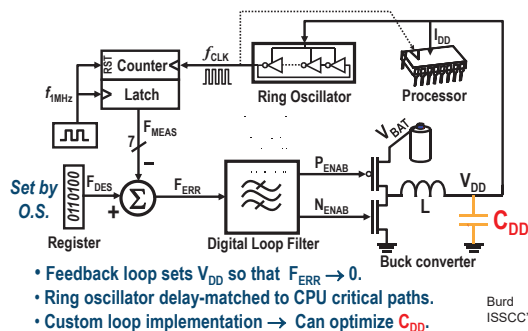
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Operating System Sets Processor Speed

- DVS requires a *voltage scheduler* (VS).
- VS predicts workload to estimate CPU cycles.
- Applications supply completion deadlines.



Converter Loop Sets V_{DD} , f_{CLK}



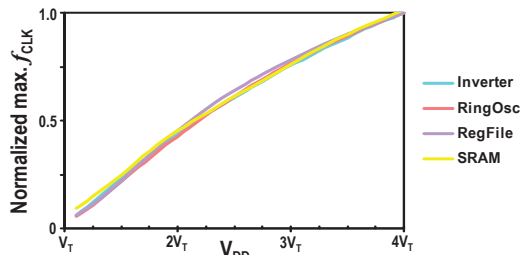
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Design Over Wide Range of Voltages

- Circuit design constraints. (Functional verification)
- Circuit delay variation. (Timing verification)
- Noise margin reduction. (Power grid, coupling)
- Delay sensitivity. (Local power distribution)

Design verification complexity similar to high-performance processor design @ fixed V_{DD}

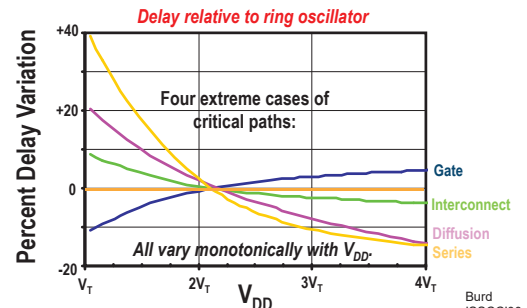
Delay Variation & Circuit Constraints



- Cannot use NMOS pass gates – fails for $V_{DD} < 2V_T$.
- Functional verification only needed at one V_{DD} value.

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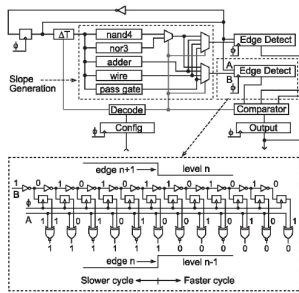
Relative Delay Variation



- Timing verification only needed at min. & max. V_{DD} .

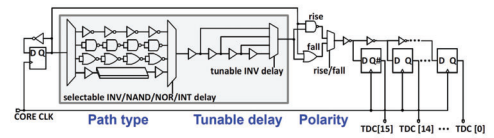
Burd
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Multiple Path Tracking



A. Drake, ISSCC'07

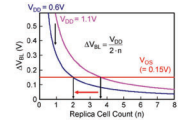
Multiple Path Tracking



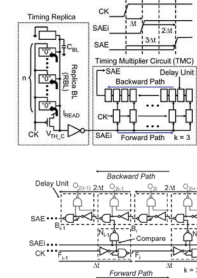
Cho, ISSCC'16

Tracking with SRAM in Critical Path

Mismatch between logic and SRAM

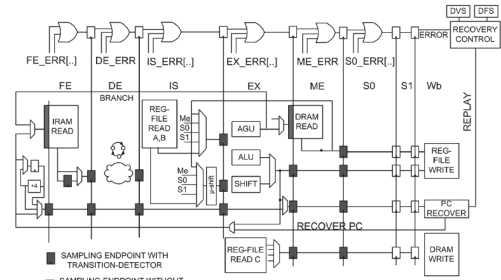


SRAM multiplicative replica



Niki, JSSC'11

Alternative: Error Detection



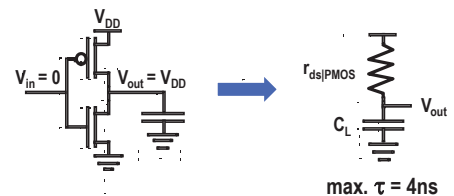
Bull, ISSCC'2010

Design for Dynamically Varying VDD

- Static CMOS logic.
- Ring oscillator.
- Dynamic logic (& tri-state busses).
- Sense amp (& memory cell).

Max. allowed $|dV_{DD}/dt| \rightarrow$ Min. $C_{DD} = 100nF$ (0.6 μm)
Circuits continue to properly operate as V_{DD} changes

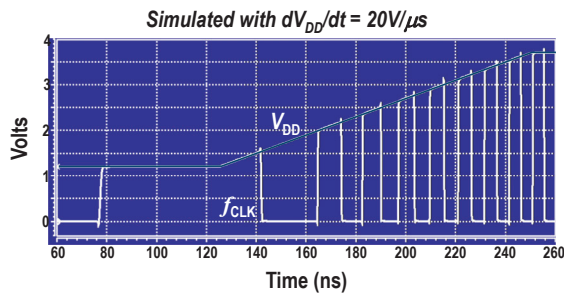
Static CMOS Logic



0.6 μm CMOS: $|dV_{DD}/dt| < 200V/\mu s$

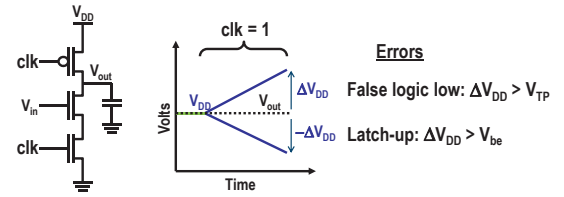
- Static CMOS robustly operates with varying V_{DD} .

Ring Oscillator



- Output f_{CLK} instantaneously adapts to new V_{DD} .

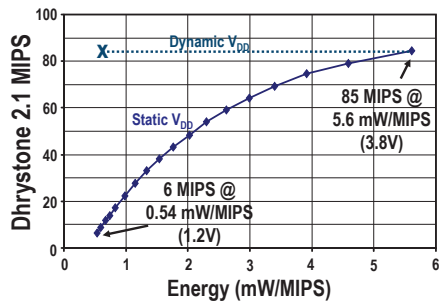
Dynamic Logic



0.6 μm CMOS: $|dV_{DD}/dt| < 20V/\mu s$

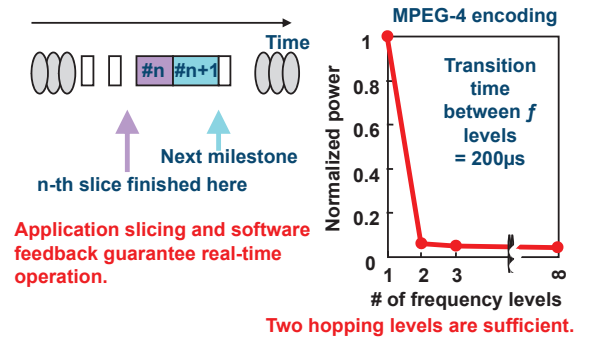
- Cannot gate clock in evaluation state.
- Tri-state busses fail similarly \rightarrow Use hold circuit.

Measured System Performance & Energy

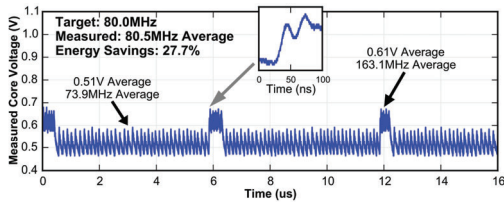


- Dynamic operation can increase energy efficiency $> 10x$.

V_{DD} -Hopping



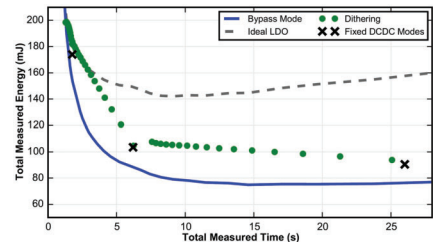
Dithering Between Supply Levels



- Done with switched-capacitor DC-DC converters which efficiently work only at discrete levels

Dithering Between Supply Levels

- Dithering fills in between fixed DC-DC modes



Next Lecture

- Low-power design
 - Clock gating
 - Power gating